

N-Channel 30V (D-S) MOSFET

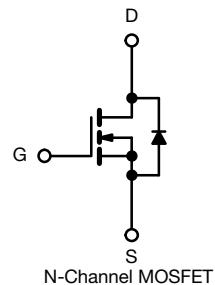
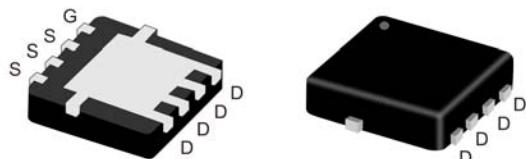
PRODUCT SUMMARY		
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A)
30	0.012 at V _{GS} = 10 V	20
	0.015 at V _{GS} = 4.5 V	20

Features

- Very Low R_{DS(on)} at 4.5V V_{GS}
- Low Gate Charge
- High Current Capability
- 100% R_g and UIS Tested
- RoHS and Halogen-Free Compliant

Pin Configuration

Power5x6



Absolute Maximum Ratings

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current	T _C = 25°C	20	A
	T _C = 70 °C	20	
Pulsed Drain Current	I _{DM}	50	
Continuous Drain Current	T _A =25°C	14	A
	T _A =70°C	11	
Avalanche Current	I _{AS} , I _{AR}	22	A
Avalanche energy L=0.1mH ^{°C}	E _{AS} , E _{AR}	24	mJ
Power Dissipation	T _C = 25°C	29.8	W
	T _C = 70 °C	19	
Power Dissipation	T _A =25°C	3.9	W
	T _A =70°C	2.5	
Junction and Storage Temperature Range	T _J , T _{STG}	-55 to 150	°C

Thermal Data

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient	t ≤ 10s	R _{θJA}	27	°C/W
Maximum Junction-to-Case	Steady-State	R _{θJC}	3.5	°C/W

Electrical Characteristics ($T_J = 25^\circ\text{C}$ Unless Otherwise Specified)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	10	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.2		2.5	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	20			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=13.8\text{A}$		9.7	12	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=12.4\text{A}$		12.2	15	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=15\text{V}, I_D=13.8\text{A}$		52		S
V_{SD}	Diode Forward Voltage	$I_S=2.6\text{A}, V_{GS}=0\text{V}$		0.8	1.2	V
I_S	Maximum Body-Diode Continuous Current ^G	$T_C = 25^\circ\text{C}$			25	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		820		pF
C_{oss}	Output Capacitance			195		pF
C_{rss}	Reverse Transfer Capacitance			73		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.36	1.8	3.6	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{DS}=15\text{V}, V_{GS}=10\text{V}, I_D=13.8\text{A}$		15	23	nC
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{DS}=15\text{V}, V_{GS}=4.5\text{V}, I_D=13.8\text{A}$		6.8	10.2	nC
Q_{gs}	Gate Source Charge			2.5		nC
Q_{gd}	Gate Drain Charge			2.3		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{DD}=15\text{V}, R_L=1.4\Omega$ $I_D \geq 11\text{A}, V_{GEN}=4.5\text{V}, R_g=1\Omega$		16	24	ns
t_r	Turn-On Rise Time			12	18	ns
$t_{D(\text{off})}$	Turn-Off DelayTime			16	24	ns
t_f	Turn-Off Fall Time			8	15	ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=11\text{A}, dI/dt=100\text{A}/\mu\text{s}, T_J=25^\circ\text{C}$		15	30	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=11\text{A}, dI/dt=100\text{A}/\mu\text{s}, T_J=25^\circ\text{C}$		6	12	nC

A. The value of R_{QJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on R_{QJA} and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 150°C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{QJA} is the sum of the thermal impedance from junction to case R_{QJC} and case to ambient.

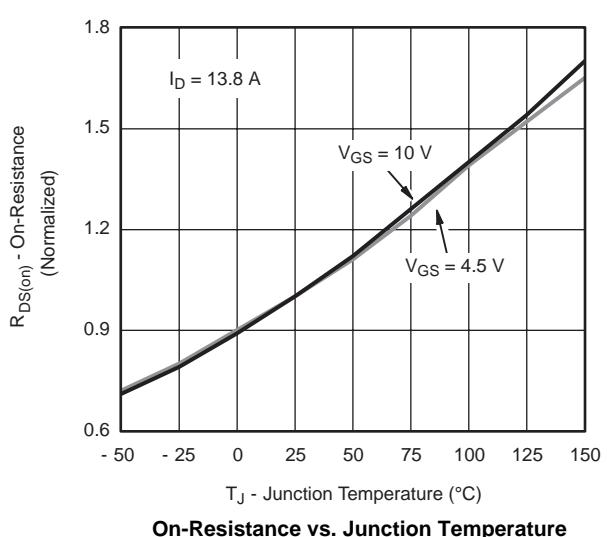
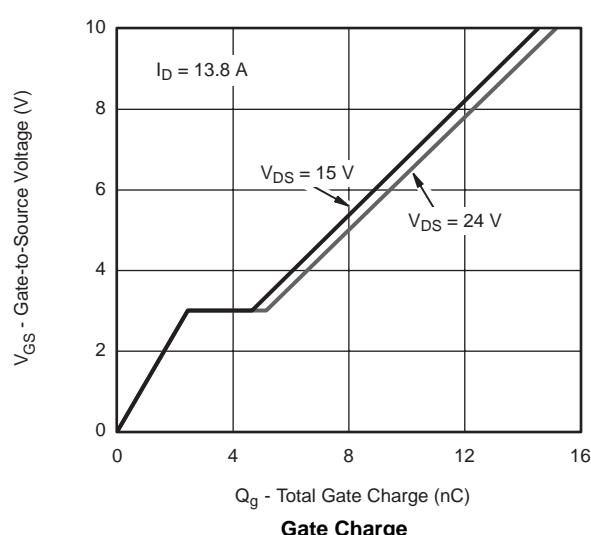
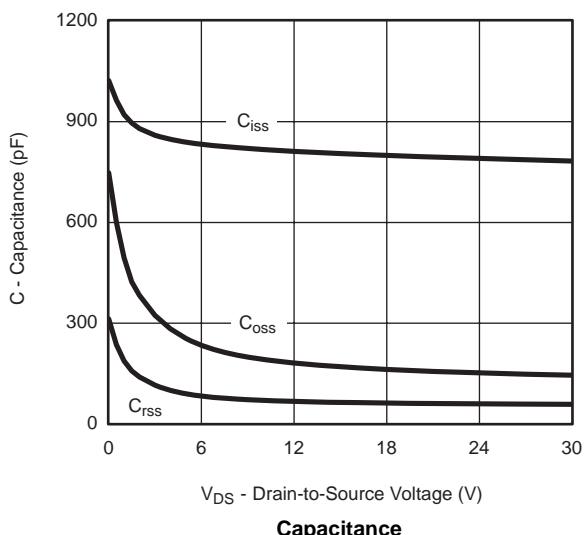
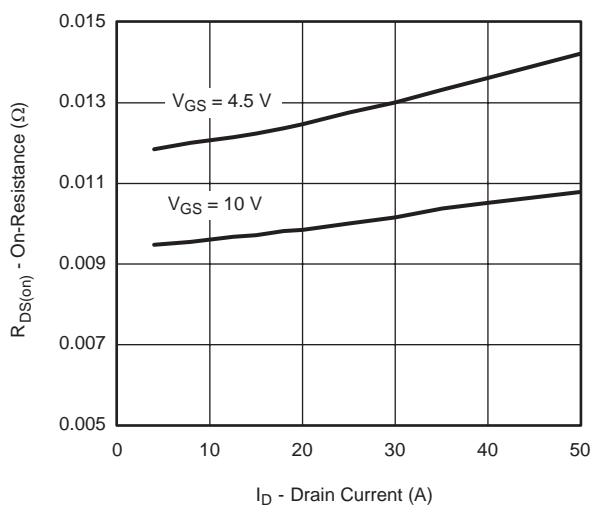
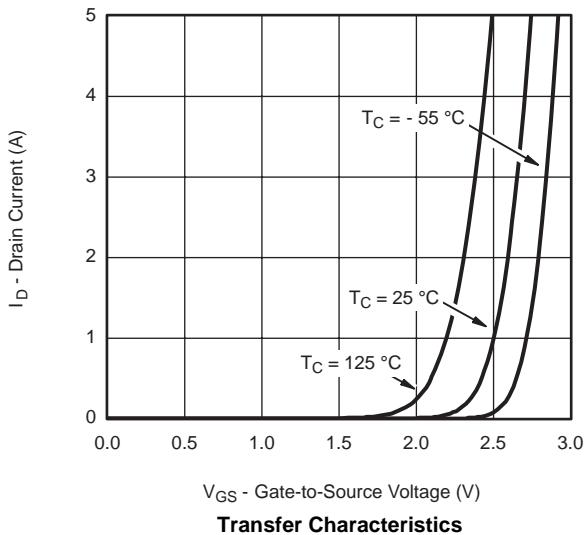
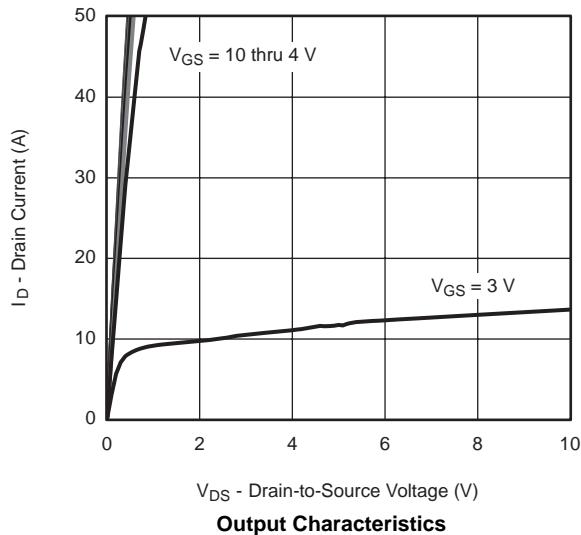
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

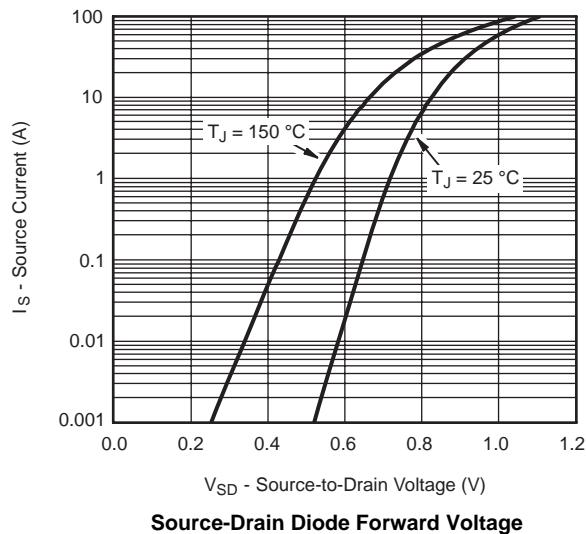
G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

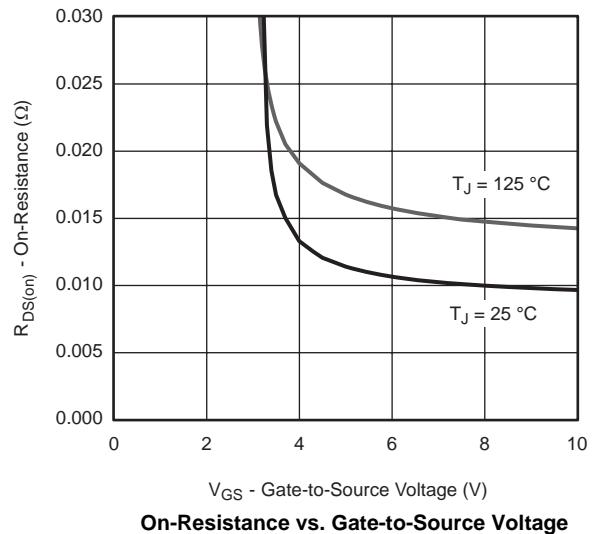
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



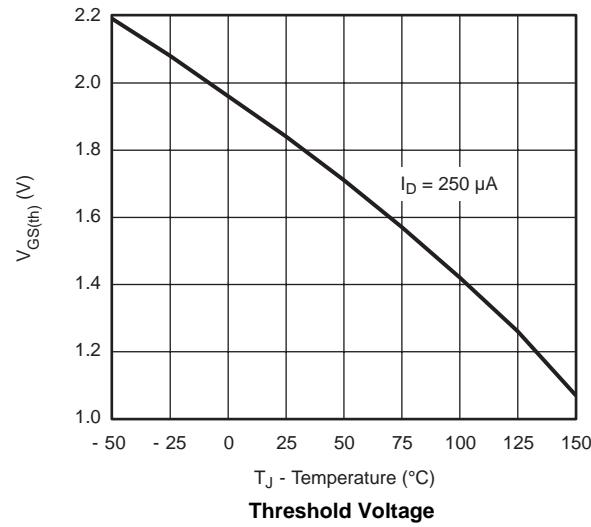
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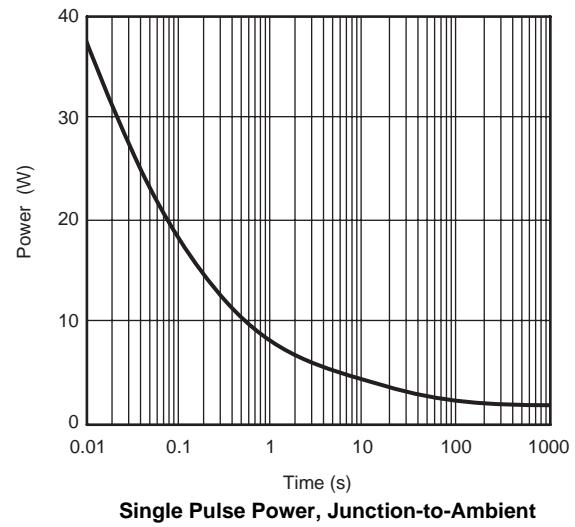
Source-Drain Diode Forward Voltage



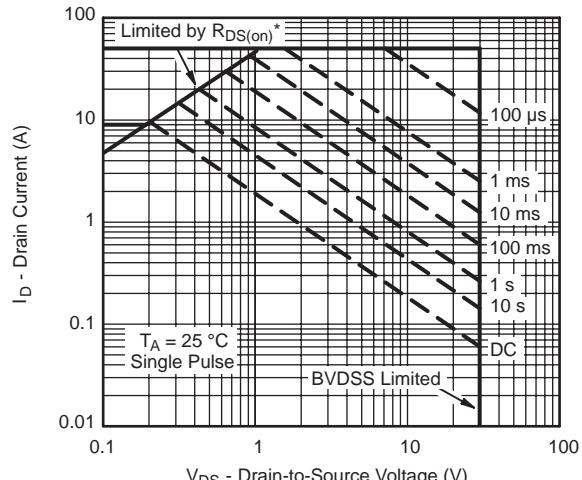
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

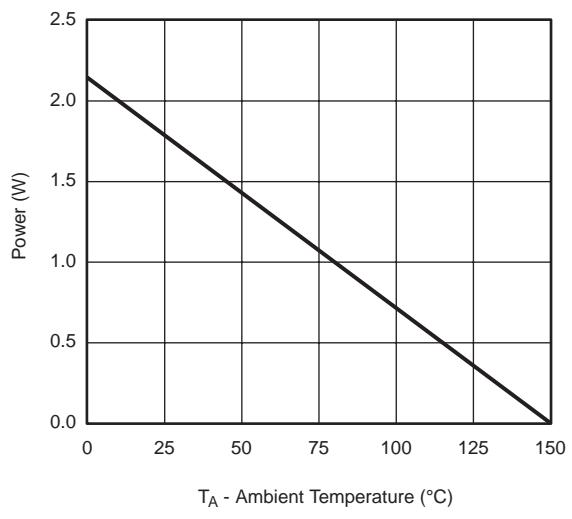
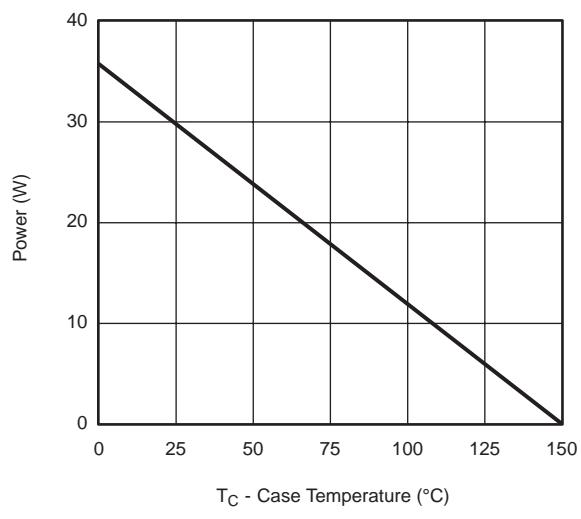
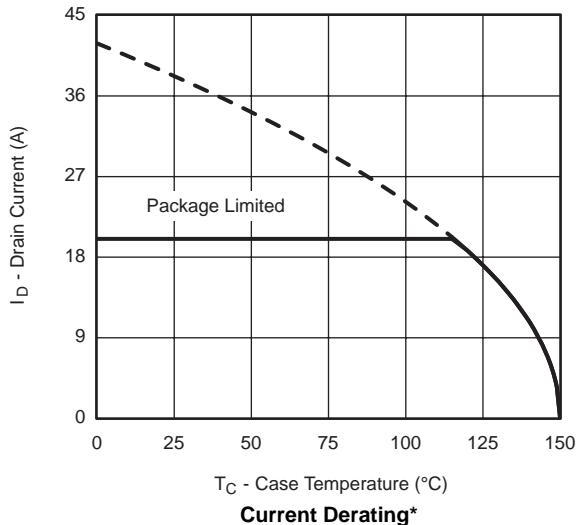


Single Pulse Power, Junction-to-Ambient

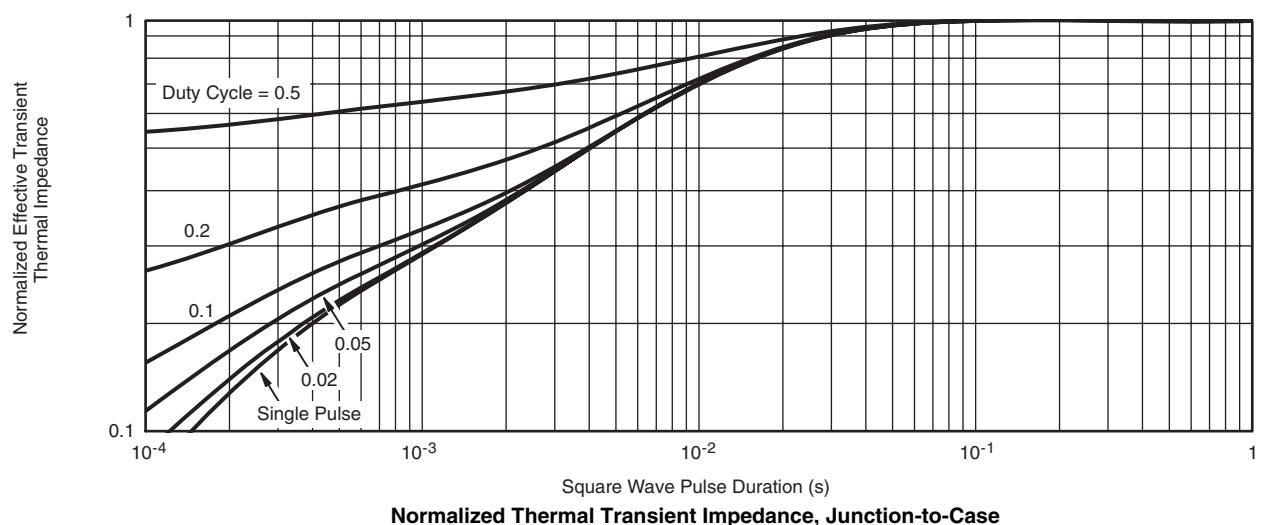
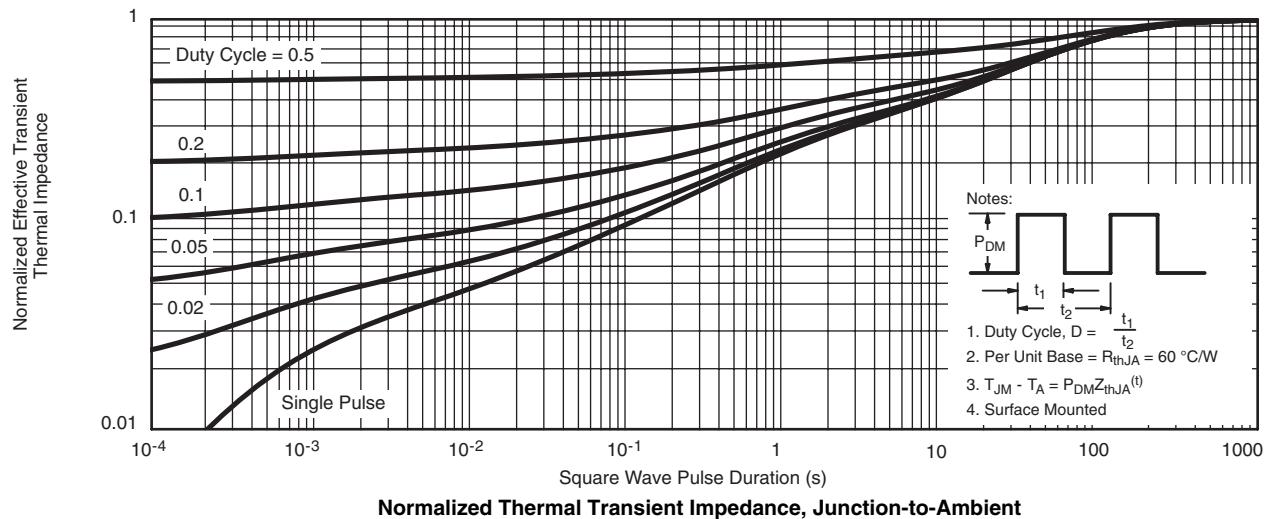


* $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified
Safe Operating Area, Junction-to-Ambient

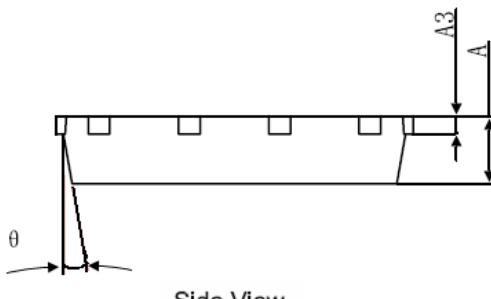
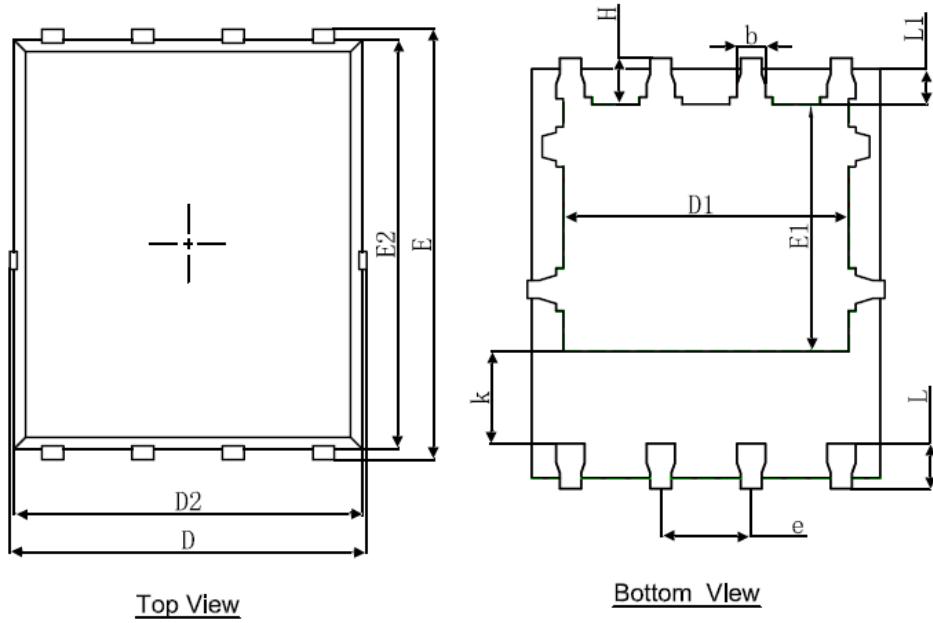
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Power5x6 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	8°		8°	
	12°		12°	